N-Channel Power MOSFET 600 V, 4.8 Ω

Features

- Low ON Resistance
- Low Gate Charge
- ESD Diode-Protected Gate
- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF	NDD	Unit
Drain-to-Source Voltage	V _{DSS}	600		٧
Continuous Drain Current $R_{\theta JC}$ (Note 1)	Ι _D	2.4	2.2	Α
Continuous Drain Current $R_{\theta JC}$ $T_A = 100^{\circ}C$ (Note 1)	I _D	1.6	1.4	Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	10	9	Α
Power Dissipation $R_{\theta JC}$	P_{D}	24	57	W
Gate-to-Source Voltage	V _{GS}	±30)	V
Single Pulse Avalanche Energy, I _D = 2.4 A	E _{AS}	120		mJ
ESD (HBM) (JESD 22-A114)	V _{esd}	2500		٧
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 17)	V _{ISO}	4500		V
Peak Diode Recovery (Note 2)	dv/dt	4.5		V/ns
Continuous Source Current (Body Diode)	Is	2.4		Α
Maximum Temperature for Soldering Leads	TL	260		°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	T _{stg} –55 to 150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

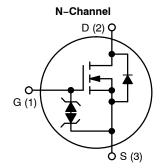
- 1. Limited by maximum junction temperature
- 2. $I_{SD} = 2.4 \text{ A}$, $di/dt \le 100 \text{ A/}\mu\text{s}$, $V_{DD} \le BV_{DSS}$, $T_J = +150^{\circ}\text{C}$



ON Semiconductor®

www.onsemi.com

V _{DSS}	R _{DS(on)} (MAX) @ 1 A
600 V	4.8 Ω





NDF02N60ZG, NDF02N60ZH TO-220FP CASE 221AH



NDD02N60Z-10 IPAK CASE 369D



NDD02N60ZT4G DPAK CASE 369AA

ORDERING AND MARKING INFORMATION

See detailed ordering, marking and shipping information on page 7 of this data sheet.

THERMAL RESISTANCE

Parameter	Symbol	Value	Unit	
Junction-to-Case (Drain)	NDF02N60Z NDD02N60Z	$R_{ heta JC}$	4.9 2.2	°C/W
Junction-to-Ambient Steady State	(Note 3) NDF02N60Z (Note 4) NDD02N60Z (Note 3) NDD02N60Z-1	$R_{ hetaJA}$	51 41 80	

^{3.} Insertion mounted

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise noted)

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		BV _{DSS}	600			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 1 mA		$\Delta BV_{DSS}/\Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current	.,	25°C	I _{DSS}			1	μΑ
	V _{DS} = 600 V, V _{GS} = 0 V	150°C				50	1
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 5)					•	•	
Static Drain-to-Source On-Resistance	V _{GS} = 10 V, I _D = 1.0) A	R _{DS(on)}		4.0	4.8	Ω
Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 50	μΑ	V _{GS(th)}	3.0	4.0	4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 1.2 A		9FS		1.7		S
DYNAMIC CHARACTERISTICS							
Input Capacitance (Note 6)	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}	215	274	325	pF
Output Capacitance (Note 6)			C _{oss}	25	34	45	1
Reverse Transfer Capacitance (Note 6)			C _{rss}	4.0	7.0	10	1
Total Gate Charge (Note 6)			Q_g	5.0	10	16	nC
Gate-to-Source Charge (Note 6)	V _{DD} = 300 V, I _D = 2.4	4 A,	Q_{gs}	1.5	2.4	4.0	1
Gate-to-Drain ("Miller") Charge (Note 6)	V _{GS} = 10 V		Q_{gd}	3.5	5.3	8.0	1
Plateau Voltage			V _{GP}		6.4		V
Gate Resistance			R _g		4.9		Ω
RESISTIVE SWITCHING CHARACTERISTI	cs				•	•	
Turn-On Delay Time			t _{d(on)}		9.0		ns
Rise Time	V _{DD} = 300 V, I _D = 2.4	4 A,	t _r		7.0		
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 5$		t _{d(off)}		15		1
Fall Time	1		t _f		7.0		1
SOURCE-DRAIN DIODE CHARACTERIST	ICS (T _C = 25°C unless other	erwise not	ed)				
Diode Forward Voltage	I _S = 2.4 A, V _{GS} = 0	V	V_{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30) V	t _{rr}		240		ns
Reverse Recovery Charge	$I_S = 2.4 \text{ A}, \text{ di/dt} = 100$		Q _{rr}		0.7		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{4.} Surface mounted on FR4 board using 1" sq. pad size, (Cu area = 1.127 in sq [2 oz] including traces).

Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.
 Guaranteed by design.

TYPICAL CHARACTERISTICS

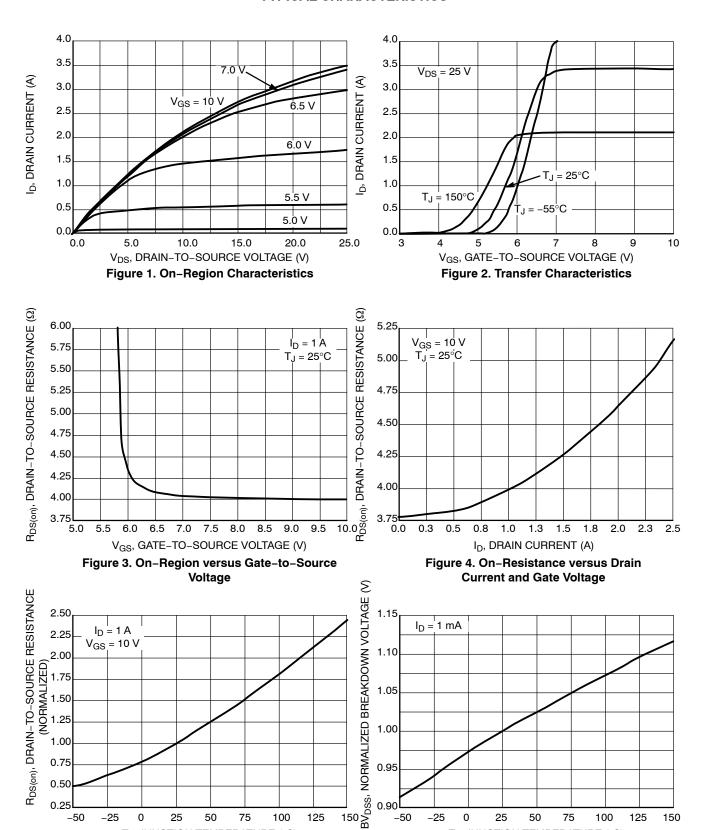


Figure 5. On-Resistance Variation with Temperature

T_J, JUNCTION TEMPERATURE (°C)

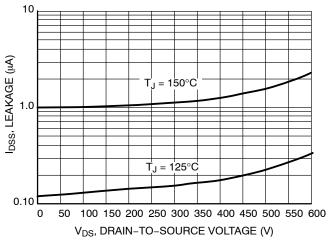
T_J, JUNCTION TEMPERATURE (°C)

Figure 6. BV_{DSS} Variation with Temperature

600 550

500

TYPICAL CHARACTERISTICS



C, CAPACITANCE (pF) 450 400 350 C_{iss} 300 250 200 150 100 50 O 0 5 15 20 25 30 35 40 45 V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Drain-to-Source Leakage Current versus Voltage

Figure 8. Capacitance Variation

 $T_J^l = 25^{l} {}^{\circ}C$ $V_{GS} = 0 V$

f = 1 MHz

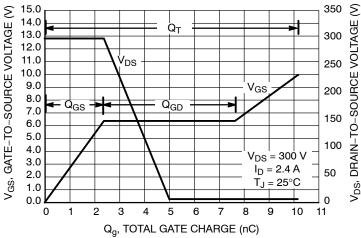
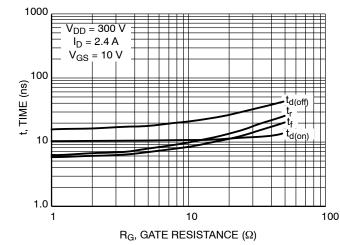


Figure 9. Gate-to-Source Voltage and Drain-to-Source Voltage versus Total Charge



10.0 SOURCE CURRENT (A) T_J = 150°C 1.0 125°C 25°C <u>ŵ</u> 0.1 0.3 0.6 0.7 0.8 0.9 1.0 V_{SD}, SOURCE-TO-DRAIN VOLTAGE (V)

Figure 10. Resistive Switching Time Variation versus Gate Resistance

Figure 11. Diode Forward Voltage versus Current

TYPICAL CHARACTERISTICS

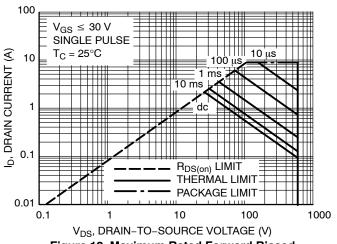


Figure 12. Maximum Rated Forward Biased Safe Operating Area NDD02N60Z

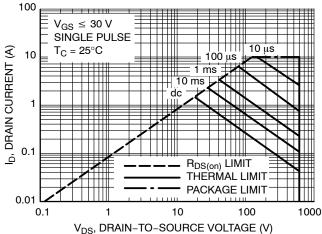


Figure 13. Maximum Rated Forward Biased Safe Operating Area NDF02N60Z

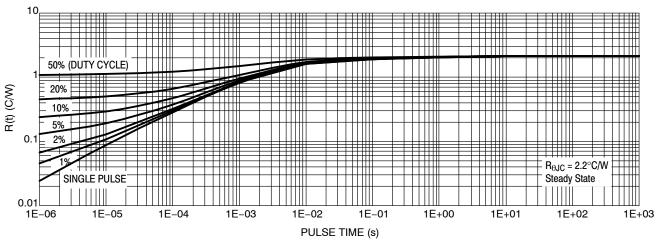


Figure 14. Thermal Impedance (Junction-to-Case) for NDD02N60Z

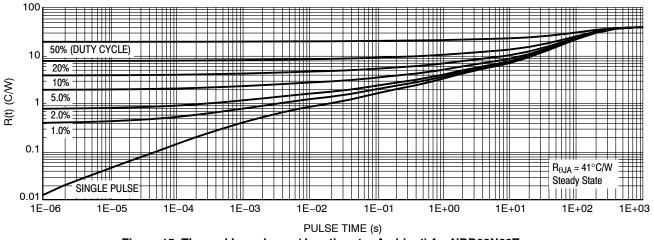


Figure 15. Thermal Impedance (Junction-to-Ambient) for NDD02N60Z

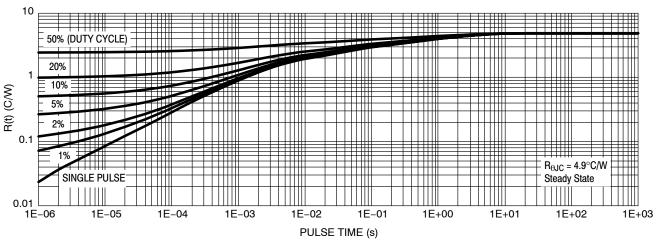


Figure 16. Thermal Impedance (Junction-to-Case) for NDF02N60Z

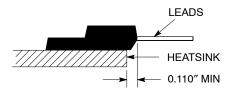


Figure 17. Isolation Test Diagram

Measurement made between leads and heatsink with all leads shorted together.

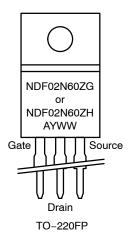
*For additional mounting information, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

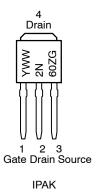
ORDERING INFORMATION

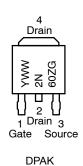
Order Number	Package	Shipping [†]
NDF02N60ZG	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDF02N60ZH	TO-220FP (Pb-Free, Halogen-Free)	50 Units / Rail
NDD02N60Z-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD02N60ZT4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MARKING DIAGRAMS





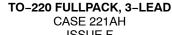


A = Location Code

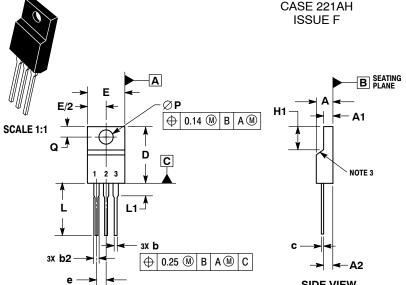
Y = Year

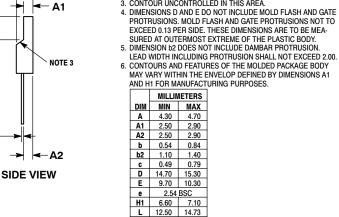
WW = Work Week

G, H = Pb-Free, Halogen-Free Package



DATE 30 SEP 2014

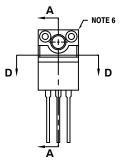


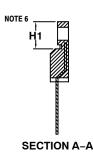


NOTES:



FRONT VIEW





ALTERNATE CONSTRUCTION

GENERIC MARKING DIAGRAM*

4.70

2.90

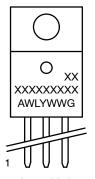
1.40

0.79

7.10

2.80 3.00 3.40

 DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS.
3. CONTOUR UNCONTROLLED IN THIS AREA.



= Assembly Location

WL = Wafer Lot

= Year

WW = Work Week

G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

STYLE 1:		STYLE 2:	
PIN 1.	MAIN TERMINAL 1	PIN 1.	CATHODE
2.	MAIN TERMINAL 2	2.	ANODE
3.	GATE	3.	GATE

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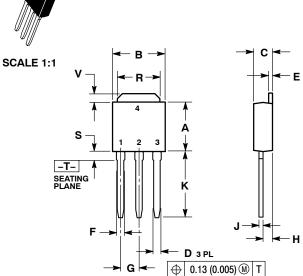
MECHANICAL CASE OUTLINE

PACKAGE DIMENSIONS





DATE 15 DEC 2010



STYLE 2:

PIN 1. GATE

3

STYLE 6: PIN 1. MT1 2. MT2 3. GATE

2. DRAIN

4. DRAIN

MT2

SOURCE

STYLE 1: PIN 1. BASE

3

STYLE 5: PIN 1. GATE

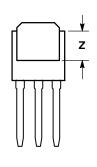
2. ANODE 3. CATHODE

ANODE

2. COLLECTOR

EMITTER

COLLECTOR



NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
Κ	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

MARKING DIAGRAMS

STYLE 4: PIN 1. CATHODE

STYLE 3: PIN 1. ANODE

2. CATHODE

4. CATHODE

3 ANODE

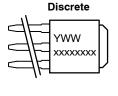
STYLE 7: PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

ANODE
 GATE

4. ANODE





xxxxxxxxx = Device Code Α = Assembly Location IL = Wafer Lot

Υ = Year WW = Work Week

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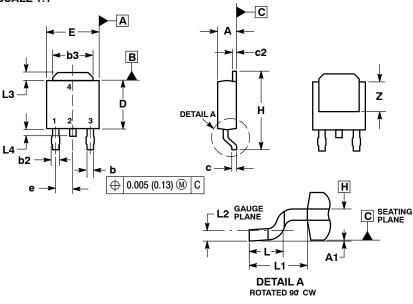


DATE 03 JUN 2010

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	REF	2.74	REF
L2	0.020 BSC		0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



STYLE 1: PIN 1. BASE 2. COLLECTOR 3. EMITTER 4. COLLECTOR

PIN 1. GATE 2. ANODE 3. CATHODE

4. ANODE

STYLE 5:

STYLE 2: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN

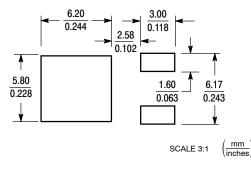
STYLE 3: PIN 1. ANODE 2. CATHODE 3. ANODE CATHODE STYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE

STYLE 6: PIN 1. MT1 2. MT2

3. GATE

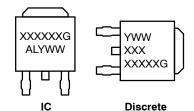
STYLE 7: PIN 1. GATE 2. COLLECTOR 3. EMITTER COLLECTOR

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

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